

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUKUI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP-03-053407	03-1991	Japan	Wataru et al	—
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NON-PATENT DOCUMENTS

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